

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/655,423	JUNG ET AL.	
	Examiner	Art Unit	
	Binh X. Tran	1765	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	696	11/17/2005	BT
438	700	11/17/2005	BT
438	706	11/17/2005	BT